

Search Notes

Application/Control No.

10/734,245

Examiner

Christopher P. Schwartz

Applicant(s)/Patent under
Reexamination

NIHEI ET AL.

Art Unit

3683

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search Updated	4/14/2006	CPS